


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559715	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  DAQUAN ZHAO	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner
386	1, 12, 46, 48, 61, 84, 94, 95	9/21/2010	dz
380	204, 221, 224	9/21/2010	dz

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT; USPGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	9/21/2010	DZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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